## Application/Control No. Applicant(s)/Patent Under Reexamination 10/023,871 WAKAI ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Tan Dean D. Nguyen 3629 **U.S. PATENT DOCUMENTS** Date Document Number Classification Name Country Code-Number-Kind Code MM-YYYY \* 11-1999 US-5,978,779 Stein et al. 705/37 Α \* US-5,918,213 06-1999 В Bernard et al. 705/26 US-С US-D US-Ε US-F US-G US-Н US-US-J

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